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Subject: TTTC: Stephan Eggersgluess Wins the TTTC's E.J. McCluskey Best Doctoral Thesis Award 2010
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Greetings Giorgio,



TTTC's Electronic Broadcasting Service

TTTC's E.J. McCluskey Best Doctoral Thesis Award

[TTTC's E.J. McCluskey Doctoral Thesis Award](#)

AWARD ANNOUNCEMENT

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Award Announcement

In a tight competition finalized at the International Test Conference (ITC) 2010 in Austin, TX, USA, Dr. Stephan Eggersgluess of the University of Bremen secured this year's TTTC's E.J. McCluskey Best Doctoral Thesis Award. Dr. Eggersgluess considered the classical problem of automatic test pattern generation, and utilized recent progress in field of Boolean satisfiability solvers to provide a framework of robust test-generation algorithms which has also been applied in an industrial context. He defended his PhD thesis at the University of Bremen, Germany, under the supervision of Professor Rolf Drechsler. Dr. Hsiu-Ming Chang, whose PhD thesis was supervised by Professor Tim Cheng of University of California, Santa Barbara, finished second. Dr. Alex Roschildt Pinto, supervised by Professor Carlos Montez of the Universidade Federal de Santa Catarina, Brazil, finished third.

In order to qualify for the finals, each of the three finalists had to win a regional semi-final competition. In 2010, the European semi-finals were held at the IEEE European Test Symposium (ETS) in Prague, Czech Republic (winner: Eggersgluess); the North American semi-finals were held at the IEEE VLSI Test Symposium (VTS) in Santa Cruz, USA (winner: Chang); and the Latin American semi-finals were held at the IEEE Latin American Test Workshop (LATW) in Punta del Este, Uruguay (winner: Pinto). In the finals as well as in each of the semi-finals, the candidates were evaluated by a jury composed of top University professors and industrial professionals in field of test and reliability. The written submissions by the candidates underwent a thorough review process, while the oral presentations by the candidates in a special session at the ITC followed by an intensive Q&A by both the jury members and the general public served to judge the communication and presentation skills of the candidates. All three candidates did extremely well, but in the end, Dr. Stephan Eggersgluess was the winner.

While congratulating Stephan and his advisor on this achievement, it is important to point out that all of the finalists made important contributions to the state of the art in our field. The E.J. McCluskey Award is not only about finding the most impactful PhD thesis, but about enhancing the impact of work done by young researchers by creating visibility. Consequently, it is not only Dr. Eggersgluess and other finalists who benefit from the Award. The test community as a whole is the main winner of this competition!

2011 Best Doctoral Thesis Award

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The 2011 Best Doctoral Thesis Award will again be held in two stages. There will be four semi-finals, with IEEE Asian Test Symposium being a new regional site. All active doctoral students working on test-related topics and recent graduates who graduated in 2009 or 2010 can participate. An individual can only participate in the contest once in a lifetime. Prospective participants are encouraged to participate when they are close to thesis completion and have obtained sufficient results. A student can freely choose the regional site to submit the summary. Submissions to multiple regional sites are prohibited.

2010 Organization

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The 2010 Award was organized by Professor Ilia Polian (University of Passau, Germany, TTTC Student Activities Chair and Global and European BDT coordinator), Dr. Haralampos Stratigopoulos (TIMA, France, North American BDT coordinator) and Professor Erika Cota (Universidade Federal do Rio Grande do Sul, Porto Alegre, Brazil, Latin American BDT coordinator). More information on the Award, including past years' winners and semi-finals of 2010, can be found under the URL http://www.tttc-events.org/tttc_website/index.php?section=awards_doctoral_thesis. Direct your questions to the TTTC Student Activities Chair, Professor Ilia Polian (Email: ilia.polian@uni-passau.de).

2010 Finals

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Results of the 2010 Finals:

1st place: Stephan Eggersgluess, University of Bremen

Title: Robust Algorithms for High Quality Test Pattern Generation using Boolean Satisfiability

2nd place: Hsiu-Ming (Sherman) Chang, UCSB

Title: Low-Cost Quality Assurance Techniques for High-Performance Mixed-Signal/RF Circuits and Systems

3rd place: Alex Roschildt Pinto, Universidade Federal de Santa Catarina, Brazil

Title: Autonomic Methods for Enhancing Communication Quality of Service in Dense Wireless Sensor Networks with Real Time Requirements

For more information, visit us on the web at: [TTTC's E.J. McCluskey Doctoral Thesis Award](#)

The Doctoral Thesis Award 2010 is sponsored by the Institute of Electrical and Electronics Engineers (IEEE) Computer Society's Test Technology Technical Council Student Activities Group (TTTC).

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